

Software Dependability:

Current Approaches and Research Gaps

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Why Software Dependability Assessment?

☞ User / customer

- Confidence in the product
- Acceptable failure rate

☞ Developer / Supplier

- During production
 - ☞ Reduce # faults (zero defect)
 - ☞ Optimize development
 - ☞ Increase operational dependability
- During operation
 - ☞ Maintenance planning
- Long term
 - ☞ Improve software dependability of next generations

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Approaches to Software Dependability Assessment

- ☞ Assessment based on software characteristics
 - Language, complexity metrics, application domain, ...
- ☞ Assessment based on measurements
 - Observation of the software behavior
- ☞ Assessment based on controlled experiments
 - Ad hoc vs standardized → benchmarking
- ☞ Assessment of the production process
 - Maturity models

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Outline of the Presentation

- ☞ Assessment based on software characteristics
 - Language, complexity metrics, application domain, ...
- ☞ **Assessment based on measurements**
 - Observation of the software behavior
- ☞ **Assessment based on controlled experiments**
 - Ad hoc vs standardized → benchmarking
- ☞ **Assessment of the production process**
 - Maturity models

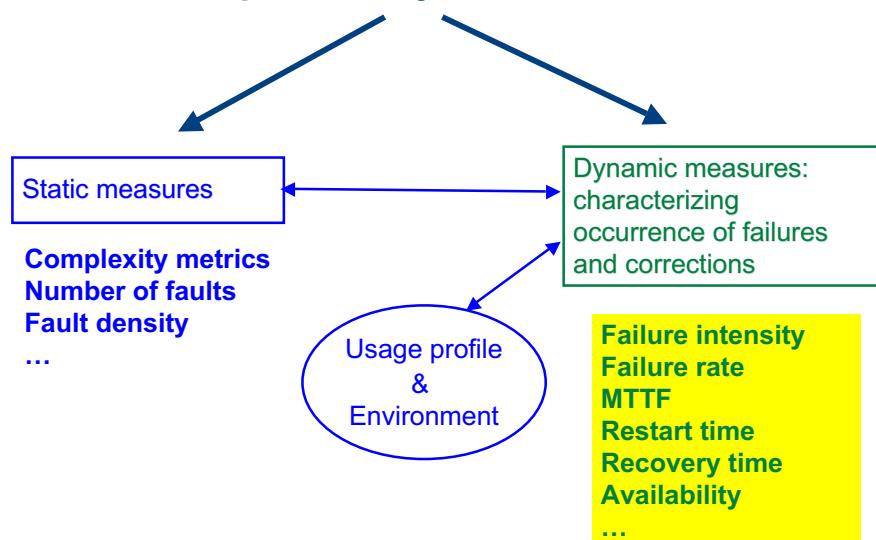
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Software Dependability Assessment — Difficulties

- ☞ Non-repetitive process
- ☞ No relationship between failures and corrections
- ☞ Continuous evolution of usage profile
 - According to the development phase
 - Within a given phase
- ☞ Overselling of early reliability “growth” models
- ☞ Judgement on quality of the software developers
- ☞ What is software dependability?
 - ☞ Number of faults, fault density, complexity?
 - ☞ MTTF, failure intensity, failure rate?

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Dependability Measures?



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Number of Faults vs MTTF

Percentage of faults and corresponding MTTF (published by IBM)

Product	MTTF (years)					MTTF (years)		
	5000	1580	500	158	50	15.8	5	1.58
1	34,2	28,8	17,8	10,3	5,0	2,1	1,2	0,7
2	34,3	28,0	18,2	9,7	4,5	3,2	1,5	0,7
3	33,7	28,5	18,0	8,7	6,5	2,8	1,4	0,4
4	34,2	28,5	18,7	11,9	4,4	2,0	0,3	0,1
5	34,2	28,5	18,4	9,4	4,4	2,9	1,4	0,7
6	32,0	28,2	20,1	11,5	5,0	2,1	0,8	0,3
7	34,0	28,5	18,5	9,9	4,5	2,7	1,4	0,6
8	31,9	27,1	18,4	11,1	6,5	2,7	1,4	1,1
9	31,2	27,6	20,4	12,8	5,6	1,9	0,5	0,0

MTTF ≤ 1.58 y

1.58 y ≤ MTTF ≤ 5 y

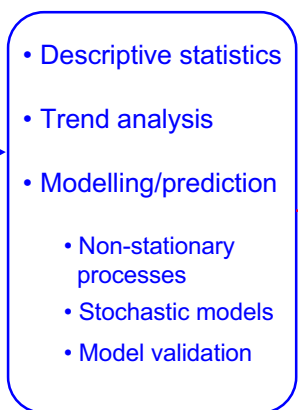
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Assessment Based on Measurements

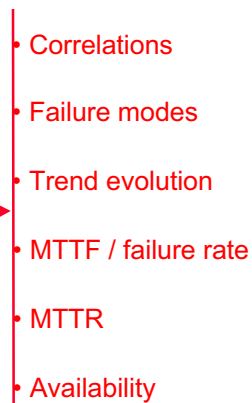
Data Collection



Data Processing

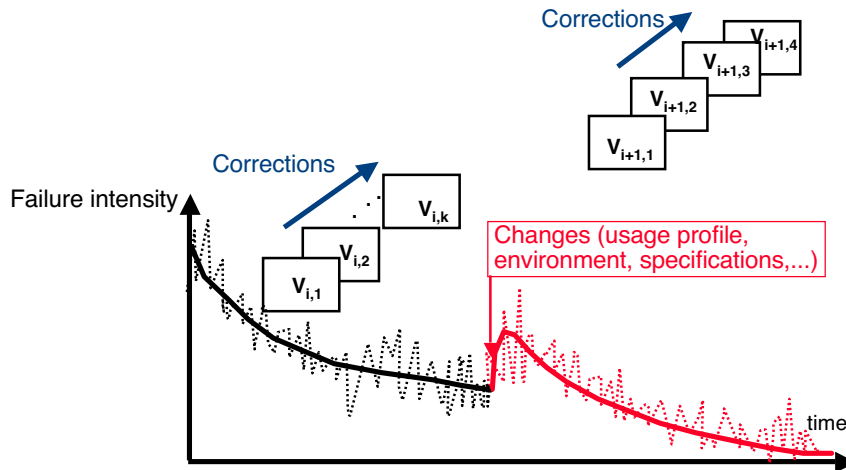


Outputs



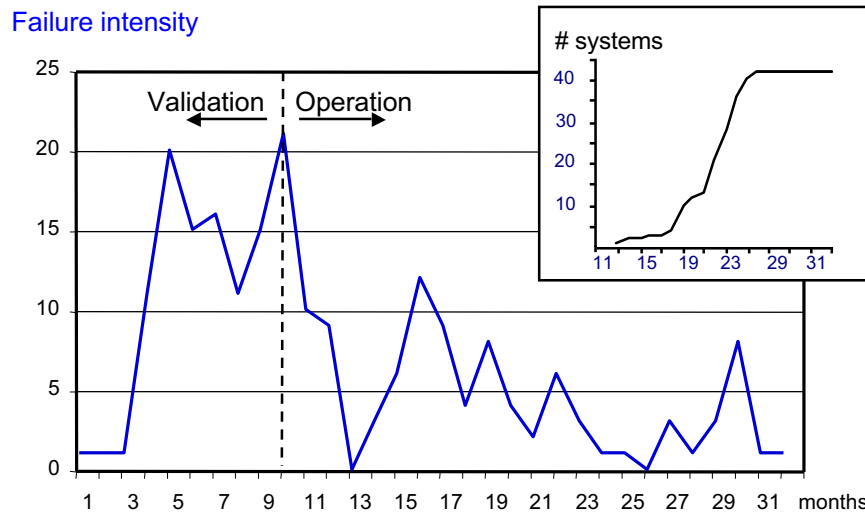
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Why Trend Analysis?



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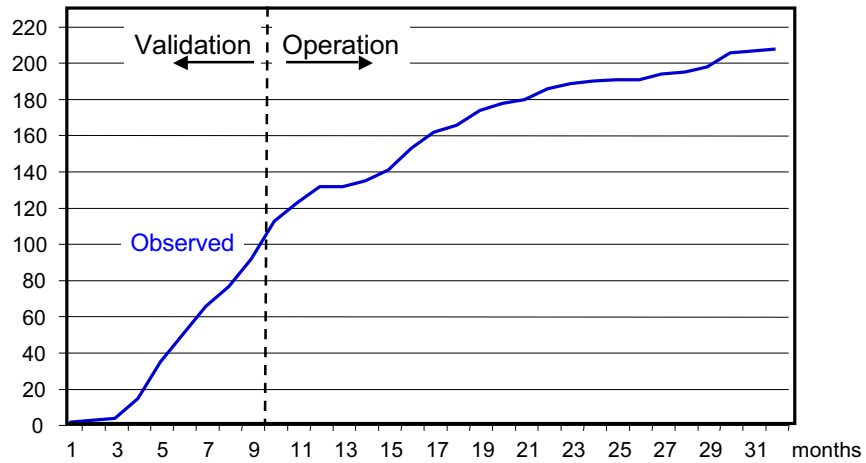
Example: Electronic Switching System



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Electronic Switching System (Cont.)

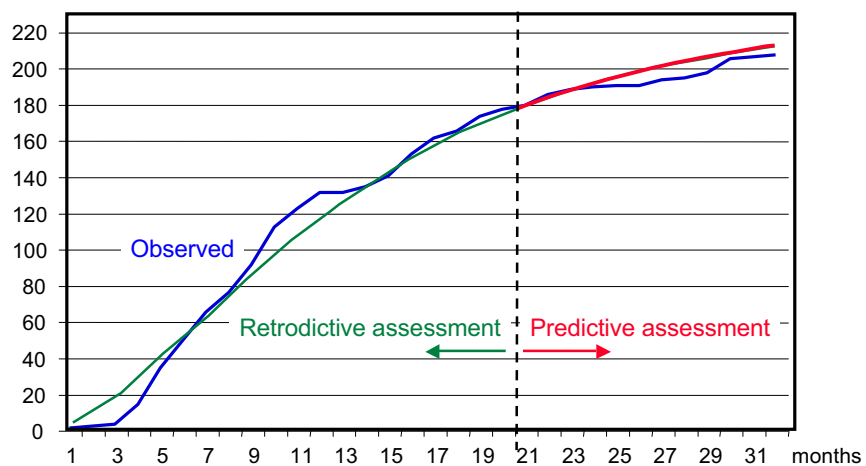
Cumulative number of failures



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Electronic Switching System (Cont.)

Cumulative number of failures → Hyperexponential model application
⇒ maintenance planning

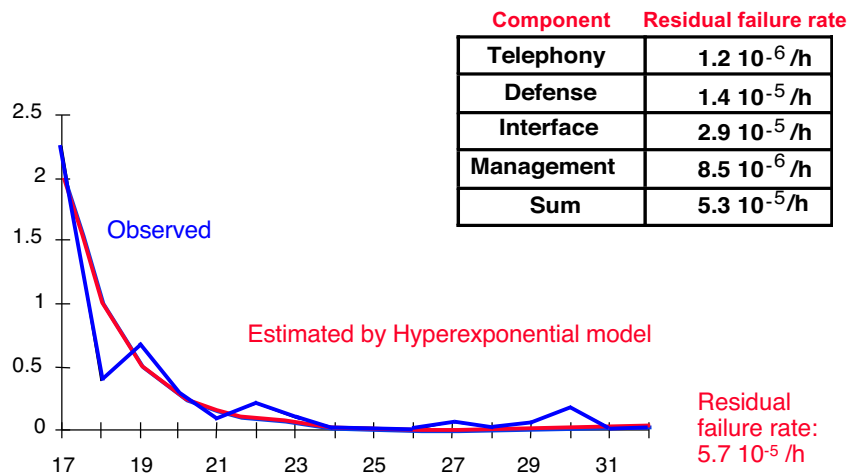


Observed # failures [20-32] = 33 Predicted # failures [21-32] = 37

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Electronic Switching System (Cont.)

Failure intensity and failure rate in operation
(for an average system)

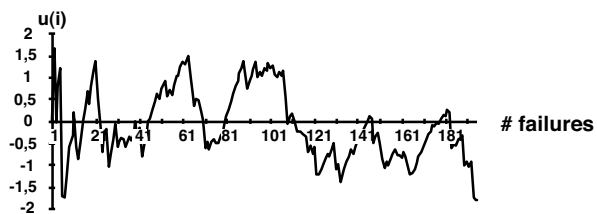


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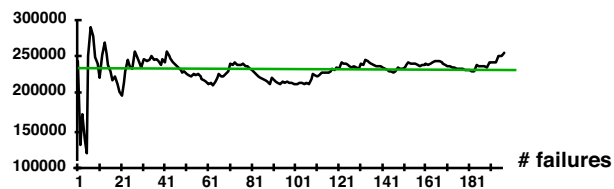
Other Example: Operating System in Operation

Data = Time to Failure during operation

Trend evolution
= stable dependability



Mean
Time to Failure



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Validity of Results

Early Validation	End of Validation	Operation
<ul style="list-style-type: none"> ☞ Trend analysis → development follow-up ☞ Assessment 	<ul style="list-style-type: none"> ☞ Trend analysis + ☞ Assessment <ul style="list-style-type: none"> • operational profile • enough data? ☞ Limits: $10^{-3}/h$ - $10^{-4}/h$ 	<ul style="list-style-type: none"> ☞ Trend analysis + ☞ Assessment High relevance <p>Examples:</p> <p>E10-B (Alcatel ESS): 1400 systems, 3 years $\lambda = 5 \cdot 10^{-6}/h$ $\lambda_c = 10^{-7}/h$</p> <p>Nuclear I&C systems: 8000 systems, 4 years $\lambda: 3 \cdot 10^{-7}/h \rightarrow 10^{-7}/h$ $\lambda_c = 4 \cdot 10^{-8}/h$</p>

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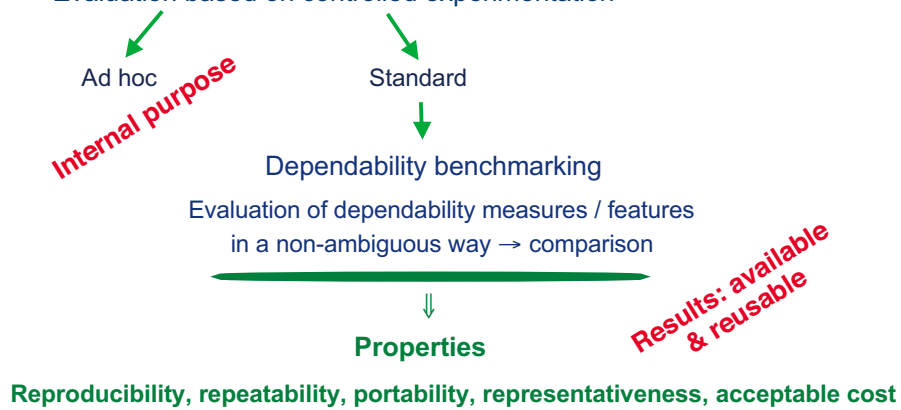
Research Gaps

- ☞ Applicability to safety critical systems
 - During development
- ☞ Applicability to new classes of systems
 - Service oriented systems
 - Adaptive and dynamic software systems \Rightarrow on-line assessment
- ☞ Industry implication
 - Confidentiality \Rightarrow real-life data
 - Cost (perceptible overhead, invisible immediate benefits)
- ☞ Case of Off-The-Shelf software components?
- ☞ Accumulation of experience \Rightarrow software process improvement
 \Rightarrow assessment of the software process

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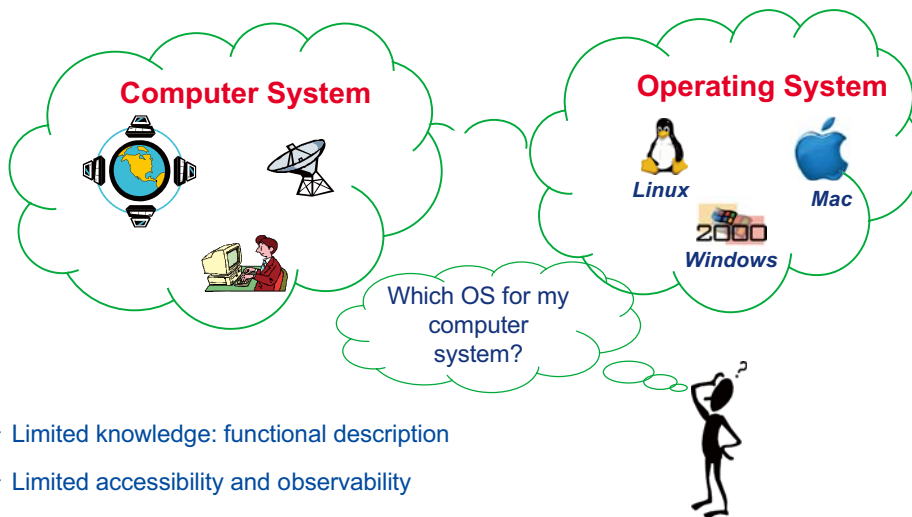
Off-The-Shelf software components — Dependability Benchmarking

- ☞ No information available from software development
- ☞ Evaluation based on controlled experimentation



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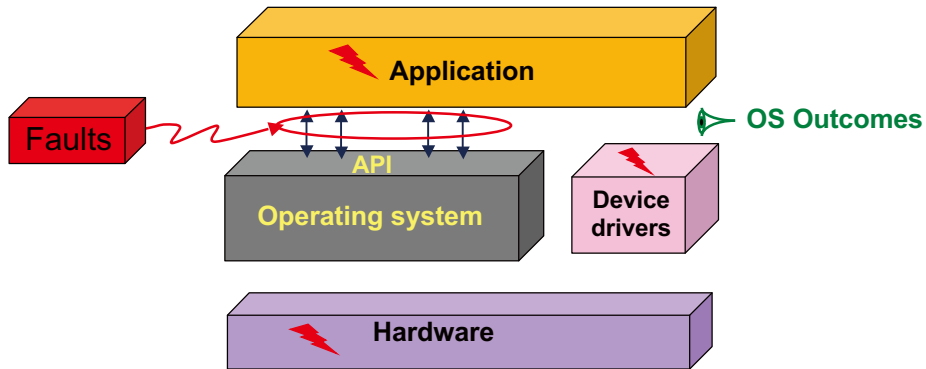
Benchmarks of Operating Systems



- ☞ Limited knowledge: functional description
 - ☞ Limited accessibility and observability
- ⇒ **Black-box approach** ⇒ **robustness benchmark**

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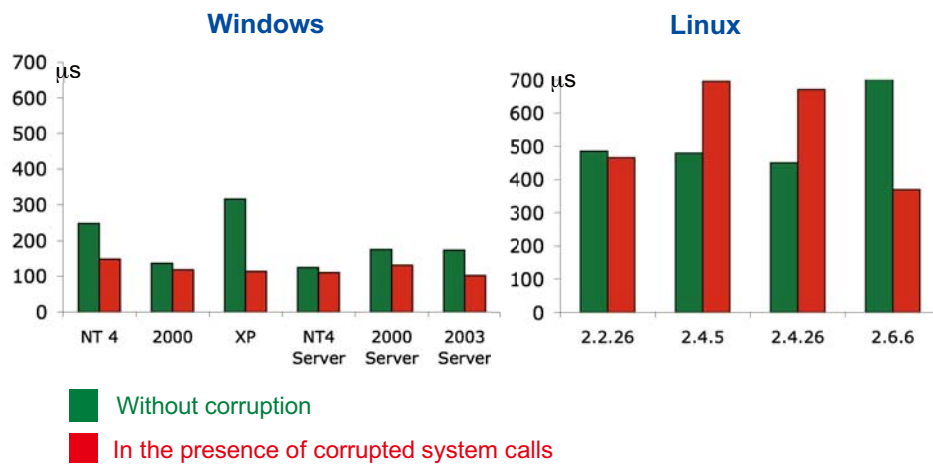
Robustness Benchmarks



Faults = corrupted system calls

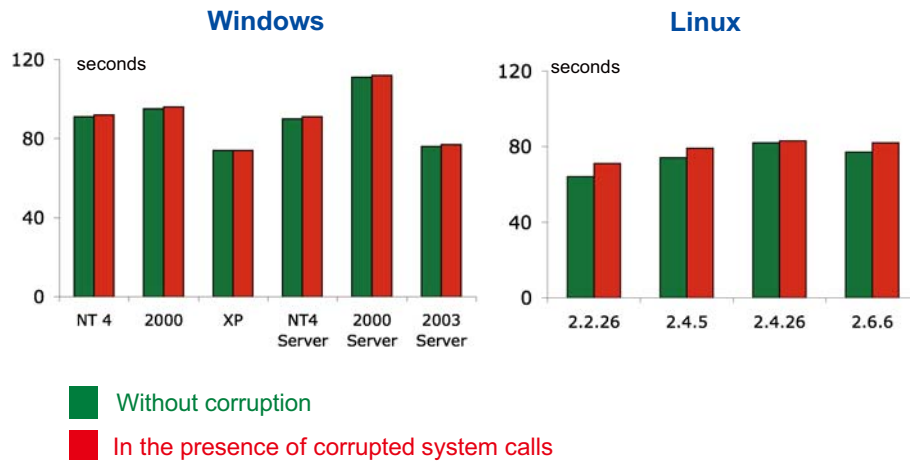
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OS Response Time to Faults in the Application



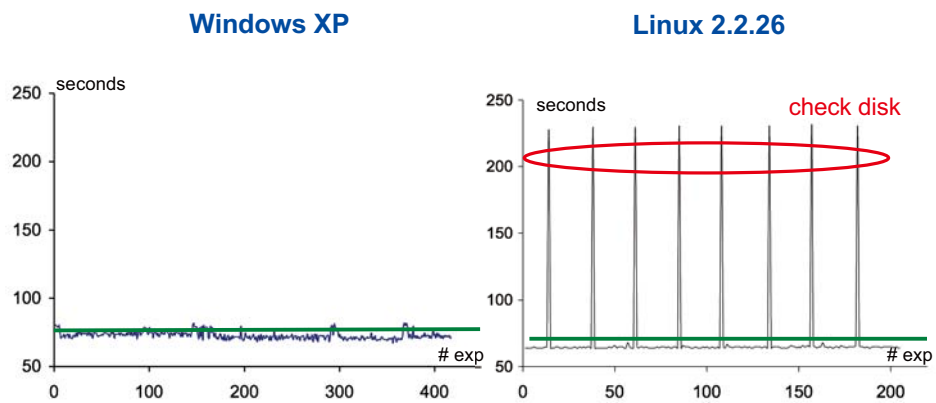
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Mean Restart Time



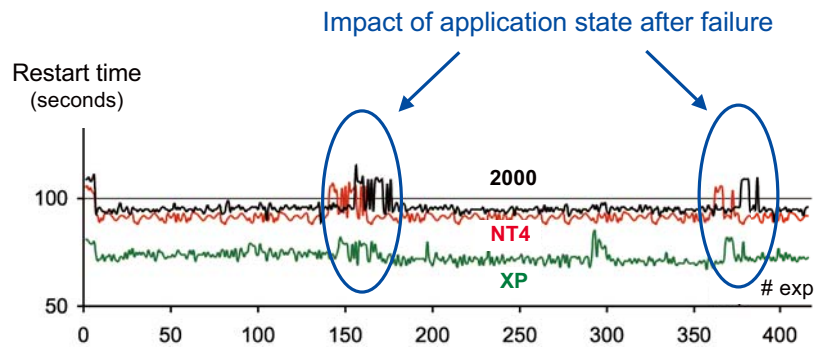
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Detailed Restart Time



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More on Windows family



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Benchmark Characteristics and Limitations

- ☞ A benchmark should not replace software test and validation
- ☞ Non-intrusiveness \Rightarrow robustness benchmarks
(faults injected outside the benchmark target)
- ☞ Make use of available inputs and outputs \rightarrow impact on measures
- ☞ Balance between cost and degree of confidence
- ☞ # dependability benchmark measures $>$
performance benchmark measures

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Maturity of Dependability Benchmarks

Dependability benchmarks

- Infancy
- Isolated work
- Not explicitly addressed
- Acceptability?

Performance benchmarks

- Mature domain
- Cooperative work
- Integrated to system development
- Accepted by all actors for competitive system comparison

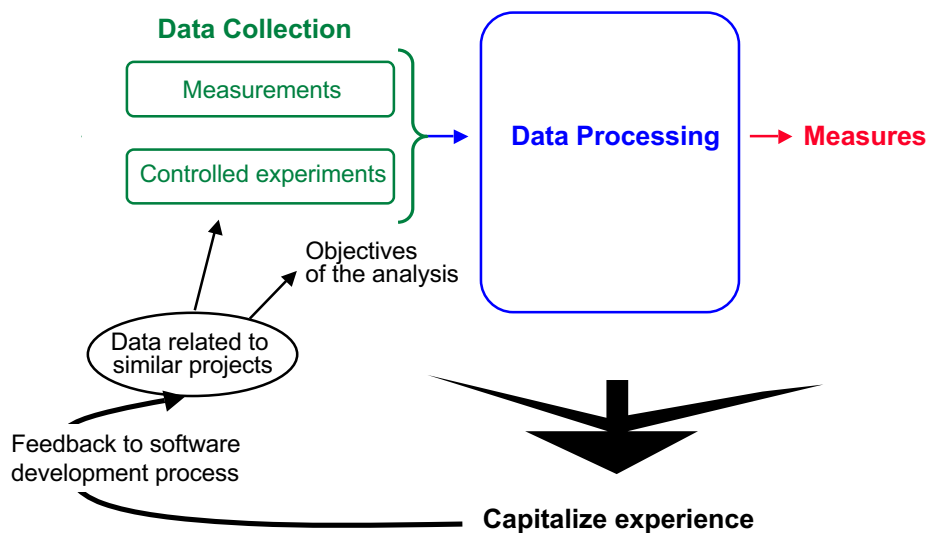
“Ad hoc” benchmarks

“Competition” benchmarks



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Software Process Improvement (SPI)

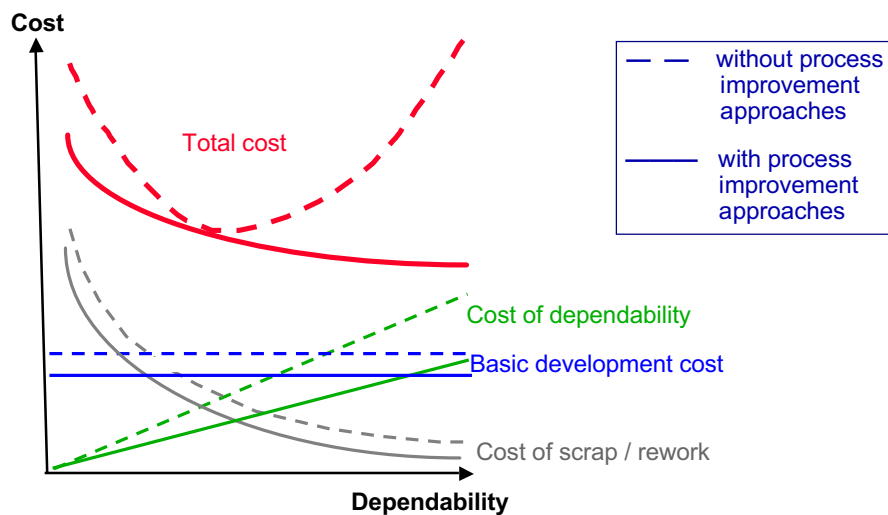


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Examples of Benefits from SPI Programs

- ☞ **AT&T**(quality program):
 - Customer reported problems divided by 10
 - Maintenance program divided by 10
 - System test interval divided by 2
 - New product introduction interval divided by 3
- ☞ **IBM** (defect prevention approach):
 - Fault density divided by 2 with an increase of 0.5 % of the product resources
- ☞ **Motorola** (Arlington Heights), mix of methods:
 - Fault density reduction = 50% within 3.5 years
- ☞ **Raytheon** (Electronic Systems), CMM:
 - Rework cost divided by 2 after two years of experience
 - Productivity increase = 190%
 - Product quality: multiplied by 4

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Process improvement ⇒ Dependability improvement & cost reduction!

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Ultimate objective:
more reliable software, faster, and cheaper!

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